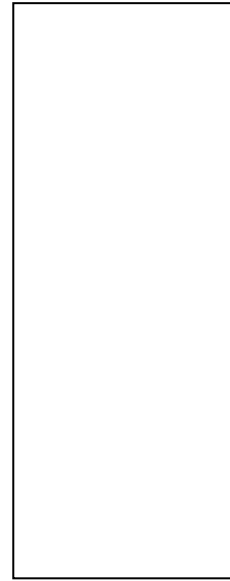


DESCRIPTION

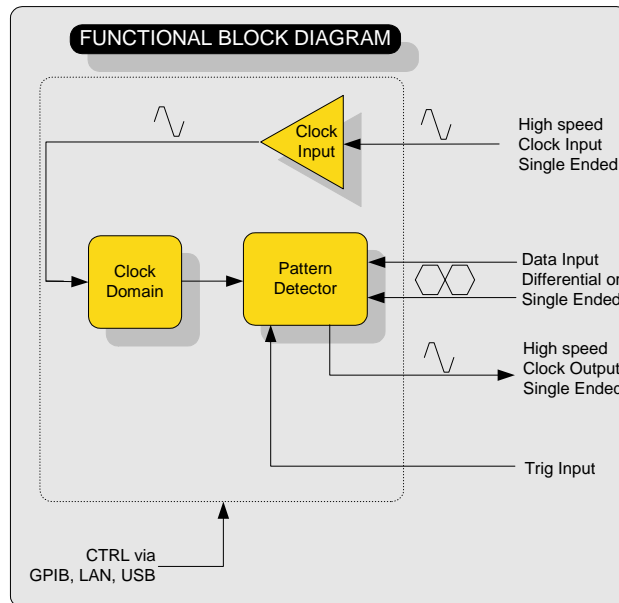
EED10-6 is an Electrical Error Detector module that plugs into the *XBERT* and *ParalleX*® Chassis. EED10-6 can receive electrical data from 1 Gbps up to 13 Gbps. Front panel indicators give immediate status for Rx Data.

KEY FEATURES

- Data Rates 1 to 13Gbps
- Differential Electrical Error Detector (SMA connector)
- PRBS: 7, 9, 10, 11, 15, 21, 23, 31
User-Pattern: 8Bit - 8Kbyte
Clock-Pattern: $\frac{1}{1}$, $\frac{1}{2}$, $\frac{1}{4}$, $\frac{1}{8}$
Additional: K28.0-K28.7, CJPAT, SSPS-64 and others
- Data input polarity swap
- External gating Input
- Automatic data alignment
- BER Detection: 0.5 to $<1E-15$
- Data log Gating-time: up to 5000h
- High speed Clock Input and Output
- LabView™ drivers available
- GPIB/LAN/USB Interface via *XBERT* Chassis.
- Small size: width 25.4mm (1")



ERROR DETECTOR MODULE PN L-6001-EED10-6



EED10-6
Module
Product
Overview

XBERT PLATFORM: LETS YOU START SMALL AND GROW



XBERT is a low-cost, modular Bit Error Rate Test Platform used for verification and test of up to 13Gbps optical and electrical chip, sub assembly and system designs. *ParalleX*® allows users to perform several BER tests at once using a single clock source. The system is ideal for developers desiring to run simultaneous BER tests on parallel interfaces or multiple independent interfaces. *XBERT* and *ParalleX*® are scalable so users can start off with a single channel and add modules to grow the system. Manufacturers can realize great savings by taking advantage of the *XBERT* and *ParalleX*® system's scalability to perform parallel testing in volume production environments.

PRELIMINARY

Error Detector Module PN L-6001-EED10-6

KEY PERFORMANCE PARAMETERS

PARAMETER	SYMBOL	Min	Max	UNIT	NOTE
Data Rate	DR	1	13	Gbps	
Data Formats			NRZ		
PRBS Pattern		7, 9, 10, 11, 15, 21, 23, 31			
User-Defined Pattern length		8	65536	Bit	
Measurable Bit Error Rate	BER	<1E-15	0.5		
Data Input Signal Amplitude Channel P or N	D _{InP/N}	100	1000	mV _{pp}	
Differential Data Input signal (D _{InDiff} =D _{InP} -D _{InN})	D _{InDiff}	200	2000	mV _{pp}	
External gating input	Gi				Starts and stops the gating measurement
Single ended Data Input Impedance	Z _{lse}	45	55	Ω	
Data Input Termination			AC -coupled		
Clock Input Amplitude		300	1000	mV _{pp}	
Clock Output Amplitude		300	1000	mV _{pp}	Not adjustable
Clock Input / Output Frequency	F _{Clk}	1	13	GHz	
Clock Input / Output Impedance	Z _{Clk}	45	55	Ω	
Clock Input / Output Termination			AC - coupled		
Operating Temperature	T _{OP}	0	40	°C	Ambient temp.

EED10-6

Module

Product

Overview

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